The design of autonomous cars is rapidly increasing the electronic content within automotive vehicles. The processing power of ICs needed for ADAS (Advanced Driver Assistance Systems) is growing exponentially, thereby pushing the complexity further. Consequently, automotive ICs that traditionally used to lag a few technology nodes for manufacturing are now using the latest technology nodes (for example 7nm) for designing and productizing such sophisticated SOCs. This tutorial will cover some of the test technologies that are being used for automotive ICs to help achieve very high test quality during manufacturing. It will also cover the in-system test requirements and the test solutions that are being deployed for key-on, key-off, and periodic testing throughout the life-span of the device.

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